Title (en)

INSPECTION MICROSCOPE FOR SEVERAL WAVELENGTH RANGES AND REFLECTION REDUCING LAYER FOR AN INSPECTION MICROSCOPE FOR SEVERAL WAVELENGTH RANGES

Title (de)

INSPEKTIONSMIKROSKOP FÜR MEHRERE WELLENLÄNGENBEREICHE UND REFLEXIONSMINDERUNGSSCHICHT FÜR EIN INSPEKTIONSMIKROSKOP FÜR MEHRERE WELLENLÄNGENBEREICHE

Title (fr)

MICROSCOPE DE CONTROLE POUR PLUSIEURS GAMMES DE LONGUEURS D'ONDE ET COUCHE ANTIREFLET DESTINEE A UN MICROSCOPE DE CONTROLE POUR PLUSIEURS GAMMES DE LONGUEURS D'ONDE

Publication

EP 1381901 A1 20040121 (DE)

Application

EP 02706779 A 20020322

Priority

- DE 10119909 A 20010423
- EP 0203217 W 20020322

Abstract (en)

[origin: WO02086579A1] An inspection microscope for several wavelength ranges with at least one illuminating beam path and at least one imaging beam path is disclosed. Those optical elements in the illuminating beam path and in the imaging beam path, through which beams of all wavelengths pass, are provided with a reflection reducing layer, by means of which the wavelength ranges with reduced reflection are the visible VIS-wavelength range up to 650 nm, the i-lines at lambda =365 nm and the ultraviolet DUV- wavelength range from 240 nm to 270 nm. The reflection reducing layer is a sandwich structure, comprising various material combinations, such as for example, M2/MgF2 or M2/MgF2/SiO2 or M2/MgF2/Al2O3, where M2 is a mixed substance from the company Merck, comprising La2O3.3,3 Al2O3. The optical components with reduced reflectance preferably comprise quartz glass or CaF2.

IPC 1-7

G02B 21/16; G02B 1/11

IPC 8 full level

G02B 1/11 (2006.01); **G02B 1/115** (2015.01); **G02B 21/00** (2006.01); **G02B 21/06** (2006.01); **G02B 21/16** (2006.01)

CPC (source: EP US)

G02B 1/115 (2013.01 - EP US); **G02B 21/0016** (2013.01 - EP US); **G02B 21/06** (2013.01 - EP US); **G02B 21/16** (2013.01 - EP US)

Citation (search report)

See references of WO 02086579A1

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DOCDB simple family (publication)

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DOCDB simple family (application)

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